

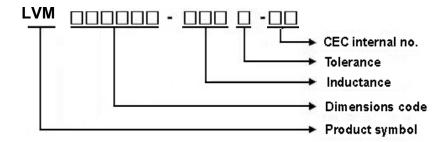
Lead-Free & RoHs Compliance!!

SPECIFICATION FOR APPROVAL

CUSTOMER:			EL TEC	н				
CUSTOMER P/N:								
OUR DWG No:		CE1-370004						
QUANTITY:	Х	Pcs.	DATE:	2013/7/3				
ITEM:		LVI	//202012-2	R2M-NT				
		ECIFICA CCEPTE						
COMPONENT								
ENGINEER								
ELECTRICAL								
ENGINEER								
MECHANICAL								
ENGINEER								
APPROVED								
REJECTED								
帝力新電子股份有限公司 CHILISIN ELECTRONICS COI NO.29,LANE 301,TEHHSIN ROAD,HUKOU, HSINCHU,TAIWAN,303, REPUBLIC OF CHINA TEL: (03) 599-2646 FAX: (03) 599-9176 E-mail: Sales@chilisin.com.tw http://www.chilisin.com.tw 台北營業處 TAIPEI OFFICE 3F,NO.233-1,PAO-CHIAO RO. HSIN TIEN,TAIPEI,TAIWAN, F TEL: (02)29112073 FAX: (02)29147698 F-mail: Sales@chilisin.com.tw	AD, LO.C.	DON YUL QIN(CHII FAX E-mi おり: SUzt TEL FAX	ANGWEI ADMII SXI TOWN, DOM IA : 00286769-773 iil:cect@chilisii J新電子(蘇州 ISIN ELECTRO	JSIN ELECTRONICS L NISTRATION AREA, NGGUANG,GUANGDO 0251-3 0232 n.com.tw 小有限公司 ONICS(SUZHOU)CO.,L ad, Suzhou New District 5568 5568	NG, TD			
DRAWN BY 陳秋霞 candy.chen		CHECKEI 惠慶 shawr		APPROV 陳瑞揚 rya				



- 1 Scope: This specification applies to SMD Power Inductor
- 2 Part Numbering: Product Identification



3 Rating:

Operating Temperature range: $-40\%\sim125\%$ (Including self - heating)

Storage Temperature range: -40°C~85°C (For products in unopened tape package -5 to 40°C)

4 Marking:

NO Marking

5 Standard Testing Condition

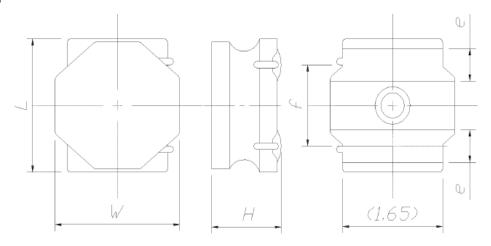
	Unless otherwise specified	In case of doubt			
Temperature	Ordinary Temperature(20±15℃)	20±2℃			
Humidity	Ordinary Humidity(65 ± 20%)	65 ± 5%			



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6 Configuration and Dimensions:



Description	Mark	Dimensions
Length	L	2.0±0.15
Width	W	2.0±0.15
Height	Н	1.2Max.
Width of Electrode	е	0.50±0.2
Space between electrodes	f	1.25±0.2

(Unit: mm)

7 ELECTRICAL CHARACTERISTICS:

Ordering Code	Nominal Inductance	Inductance Tolerance	D.C. Resistance [mΩ]		Rated Current [mA]			
	[µH]	[%]	Тур	Max	Saturation Current Idc1(Typ)	Temperature Rise Current Idc2(Typ)	Saturation Current Idc1(max)	Rise Current
					idei(Typ)	iucz(Typ)	luc I(ITIax)	ldc2(max)
LVM202012-2R2M-NT	2.2	±20	95	109	2000	1550	1750	1450

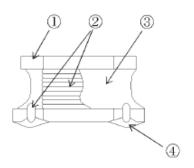
Absolute maximum voltage: DC25V

- *) The saturation current value (ldc1) is the DC current value having inductance decrease down to 30%. (at 20 deg C)
- *) The temperature rise current value (Idc2) is the DC current value having temperature increase up to 40 deg C. (at 20 deg C)
- *) The rated current is the DC current value that satisfies both of current saturation current value and temperature rise current value.

※ Caution for Temperature Rise.	
Temperature rise of this inductor depends on the installed board condition.	
It shall be confirmed in the actual end product that temperature rise of inductor is within	
operating temperature.	

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structural drawing



① Core

Metal magnetic core

2 Winding wire

Polyurethane-copper wire

③ Over-coating resin

Epoxy resin, containing Metal magnetic powder

④ Electrode

External electrode (substrate)

Αg

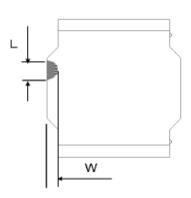
External electrode (top surface solder coating)

Sn-Ag-Cu



Core chipping

The appearance standard of the chipping size in top side, of bottom side metal magnetic core is following dimension.



L	W				
0.4mmMax.	0.4mmMax.				



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10 TEST DATA FOR PREPRODUCTION SAMPLES

QF-1419

DE	SCRIP1	TION: L	/M2020	12-2R2N	I-NT							
	IEAS. Item	L (uH)	RDC (mΩ)Max	Isat (mA)Typ.		L m/m	W m/m	H m/m				
Spec	Customer	2.2±20%										
	Suggest		109	2000	2	2.0±0.15	2.0±0.15	1.2 Max.				
Tes	st Freq.	1MHz 1V										
	1	1.96	106	2000		2.06	2.04	1.15				
	2	1.94	104	2100		2.06	2.04	1.16				
	3	2.00	105	2000		2.07	2.05	1.14				
	4	1.92	108	2100		2.06	2.05	1.14				
	5	1.94	106	2100		2.07	2.06	1.13				
	6											
	7											
	8											
	9											
	10											
	11											
	12											
	13											
	14											
	15											
	X	1.952	105.8	2060		2.064	2.048	1.144				
	R	0.08	4	100		0.01	0.02	0.03				
CUS	STOMER											
S	AMPLE											

TEST INSTRUMENT:

L: Agilent/HP4284A+Agilent/HP42841A

RDC: DIGITAL MILLIOHM METER Chroma 16502, or equivalent

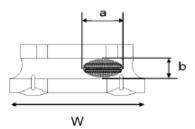
Isat & Irms: Agilent/HP4284A+Agilent/HP42841A



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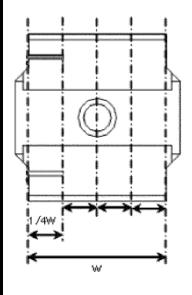
Exposed wire tolerance limit of coating resin part on product side Size of exposed wire occurring to coating resin is specified below.



- ① Width direction(dimension a) : Acceptable when a<=w/2
 Nonconforming when a>w/2
- ② Length direction (dimension b): Dimension b is not specified.
- When total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, that is acceptable.



Electrode appearance criterion for exposed wire



Cross section of joint part	Appearance judgment
Only top side of wire is exposed. (regardless of whole tope side of wire exposed)	Good
Wire is soldered insufficiently and less than half of outer diameter is covered with solder.	Less than one-quarter of width of insufficiently soldered portion shall be acceptable. (More than one-quarter shall be segregated as reject.)



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13 MECHANICAL Characteristics The test samples shall be soldered to the test board Resistance to No damage. deflection by the reflow soldering conditions show in Table 15 As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2 mm. Force Rod Sample 20.65 Land dimensions Test board size : $100 \times 40 \times 1.0$ Test board material: glass epoxy-resin Solder cream thickness: 0.1 Unit: mm Shall not come off PC The test samples shall be soldered to the test board Adhesion of Terminal board by the reflow soldering conditions shown in Table 15 electrode ♦ 10 N, 5 s Applied force: 10 N to X and Y directions. Duration: 5 s. Solder cream thickness: 0.1 mm (Refer to recommended Land Pattern Dimensions defined in "Precaution") Applied force: 20 N Body strength No damage. Duration: 10 s R0.5 mm _ Sample 0.6W



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14 ENVIRONMENT TESTS

<u>-</u>							
Test Item	Standard	Test method					
Resistance to vibration	ΔL/L : within±10 % No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 Then it shall be submitted to below test conditions.					
		Frequency range 10Hz ~55 Hz					
		Total Amplitude 1.5 mm (May not exceed acceleration 196 m/S²)					
		Sweeping Method 10Hz to 55Hz to 10 Hz for 1 min.					
		Time For 2 hours on each X, Y, and Z axis.					
Resistance to soldering heat (Reflow)	ΔL/L : within±10 % No abnormality observed in appearance.	The test sample shall be exposed to reflow oven at 230±5 deg C for 40 seconds, with peak temperature at 260±5 deg C for 5 seconds, 2 times.					
		Test board thickness: 1.0 mm Test board material: glass epoxy-resin					
Solderability	At least 90 % of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below table. Flux: Methanol solution containing rosin 25 %.					
		Solder Temperature 245±5 deg C					
		Time 5±1.0 s.					
		Immersing Speed 25 mm/s					
Temperature characteristics	ΔL/L : within±10 % No abnormality observed in appearance.	Measurement of inductance shall be taken at temperature range within -40 deg C to +125 deg C. With reference to inductance value at +20 deg C, change rate shall be calculated.					
Thermal shock	ΔL/L : within±10 % No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed at specified temperature for specified time by step 1 to step 4 as shown in below table in sequence. The temperature cycle shall be repeated 100 cycles. Conditions of steps for 1 cycle					
		Step Temperature Time (min)					
		1 -40±3 deg C 30±3					
		2 Room Temp. 3 maximum					
		3 85±2 deg C 30±3					
		4 Room Temp 3 maximum					
Low temperature life test	ΔL/L : within±10 % No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 After that, the test samples shall be placed at test conditions as shown in below table.					
		Temperature -40±2 deg C					
		Time 500 +24/-0 h					



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14 ENVIRONMENT TESTS

Test Item Loading at high temperature life test Loading at high temperature life in appearance. The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and applied the rated current continuously as shown in below table. Temperature 85±2 deg C Applied current (Refer to Table 1) Time 500 +24/-0 h The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and humidity as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Time 500 +24/-0 h The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current Rated current (Refer to Table 1) Time 500 +24/-0 h The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current (Refer to Table 1) Time 500 +24/-0 h		I							
temperature life test No abnormality observed in appearance. No abnormality observed in appearance. The test samples shall be placed in thermostatic oven set at specified temperature and applied the rated current continuously as shown in below table. Temperature 85±2 deg C Applied current (Refer to Table 1) Time 500+24/-0 h AL/L: within±10 % No abnormality observed in appearance. The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Time 500+24/-0 h Loading under damp heat life test No abnormality observed in appearance. The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. The test samples shall be placed to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current (Refer to Table 1)	Test Item	Standard							
Applied current Rated current (Refer to Table 1) Time 500 +24/-0 h	temperature life	No abnormality observed	the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostati oven set at specified temperature and applied th						
Applied current Rated current (Refer to Table 1) Time 500 +24/-0 h			Temperature	85±2 deg C					
Damp heat life test No abnormality observed in appearance. The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Time 500 +24/-0 h The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current Rated current (Refer to Table 1)				Rated current					
test No abnormality observed in appearance. No abnormality observed in appearance. The test samples shall be placed in thermostatic oven set at specified temperature and humidity as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Time 500 +24/-0 h The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current Rated current (Refer to Table 1)			Time	500 +24/-0 h					
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Time 500 +24/-0 h Loading under damp heat life test No abnormality observed in appearance. The test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90∼95 %RH Applied current (Refer to Table 1)			Temperature	60±2 deg C					
Loading under damp heat life test Description			Humidity	90∼95 %RH					
damp heat life test test No abnormality observed in appearance. No abnormality observed in appearance. In a test samples shall be soldered to the test board by the reflow soldering conditions shown in Table 15. The test samples shall be placed in thermostatic oven set at specified temperature and humidity and applied the rated current continuously as shown in below table. Temperature 60±2 deg C Humidity 90~95 %RH Applied current (Refer to Table 1)			Time	500 +24/-0 h					
Humidity 90~95 %RH Applied current (Refer to Table 1)	damp heat life	No abnormality observed	the reflow soldering conditions shown in Table 15 The test samples shall be placed in thermostations set at specified temperature and humidity and a						
Applied current (Refer to Table 1)			Temperature 60±2 deg C						
Applied current (Refer to Table 1)			Humidity						
Time 500 +24/-0 h			Applied current	11					
			Time	500 +24/-0 h					

Standard	Unless otherwise specified, the test samples are placed at room temperature
	and humidity and measured within 48 hours after exposure to test conditions.
condition	and numberly and measured within 40 hours after exposure to test conditions.



15 ENVIRONMENT TESTS [deg] 5s Max. 260-- Peak: 250+5/-0 deg C 240-- 230deg C Min. 220-30±10 s 200-150~180 deg C 180. Temperature 90±30 s 100 80-

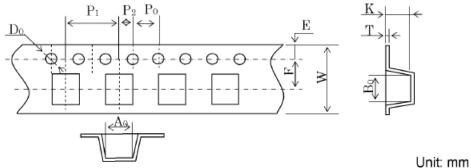
The products may be exposed to reflow soldering process of above profile up to two times.

* Temperature on surface of circuit board.

Time(s)

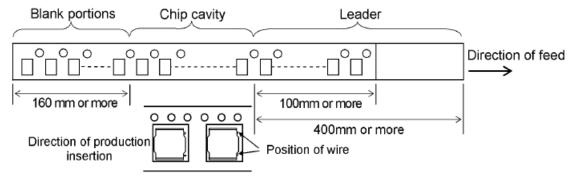


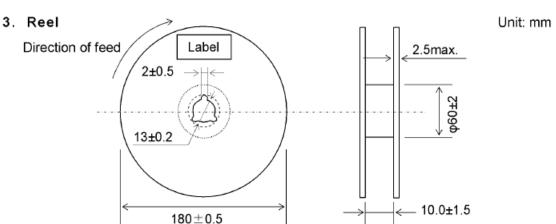
1. Dimensions



A ₀	B ₀	W	F	Е	P ₁	P ₂	P ₀	D ₀	Т	K
2.2 ±0.1	2.2 ±0.1	8.0 ±0.2	3.5 ±0.1	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1		0.25 ±0.05	

2. Direction of rolling





Label position: On the opposite side of sprocket holes side of reel

4. Top tape strength



Peel-off strength : $0.1 \text{ N}{\sim}1.3 \text{ N}$ Peel-off angle : $165^{\circ} \sim 180^{\circ}$ Peel-off speed : 300 mm/min



17 PACKING FORM

1. The number of components

A tape & reel package contains 2500 inductors.

2. Tape and Reel

Emboss carrier tape: 8mm-width and 4 mm-pitch

Reel: 180 mm-diameter

3. The allowable number of empty chip cavities

Maximum two (2) chip cavities missing product may exist in a reel but they may not be consecutive two cavities.

4. Marking

The following items shall be marked legibly on per tape & reel package.

- (1) Customer part No.
- (2) Our part No.
- (3) Supplier name (TAIYO YUDEN CO., LTD.)
- (4) Control No.
- (5) Date (stamp)
- (6) Quantity
- (7) Country of the origin

5. Dimensions of packing box (for Tape & Reel package)

Length	135 mm	
Width	185 mm	
Height	185 mm	

Standard Quantity: 25000 pcs.

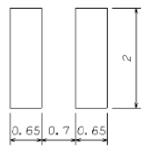
A packing box contains 10 reels maximum.



16 Precautions

1. Surface Mounting

- · Mounting and soldering conditions should be checked beforehand.
- · Applicable soldering process to this products is reflow soldering only.
- Recommended Land-Pattern :



(Unit: mm)

2. Handling

- · Keep the products away from all magnets and magnetic objects.
- Be careful not to subject the products to excessive mechanical shocks.
- · Please avoid applying impact to the products after mounted on pc board.
- Avoid ultrasonic cleaning.
- Between the terminals on the bottom of the products, please do not provided pattern.
 Parts are arranged around the products (top panel, side) on the surface of the products.
 Please do not contact.

Storage

To prevent deterioration of the solderability of terminal electrodes and/or the packing materials of the products, please store the products under following storage conditions.

Ambient temperature range -5 deg C to 40 deg C Humidity 70 % RH maximum

Even under the ideal storage conditions, solderability of inductor's electrode deteriorates as time passes, so inductors should be used within 6 months after the delivery time.

4. Regarding Regulations

- Any Class-I or Class-II ozone-depleting substance (ODS) listed in the Clean Air Act in US for regulation is not included in the products or applied to the products at any stage of whose manufacturing processes.
- · Certain brominated flame retardants (PBBs, PBDEs) are not used at all.
- The products of this specifications are not subject to the Export Trade Control Order in Japan or the Export Administration Regulations in US.

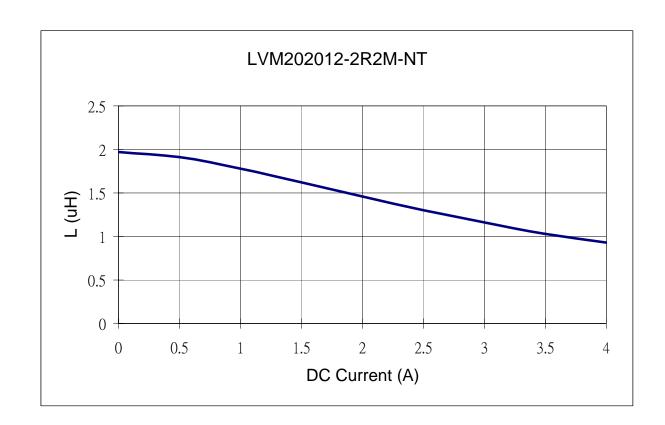
5. RoHS compliance

This product conforms to "RoHS compliance".



14 Curve:

IDC(A)	L(uH)
0.0	1.97
0.5	1.91
1.0	1.78
1.5	1.62
2.0	1.46
2.5	1.30
3.0	1.16
3.5	1.03
4.0	0.93

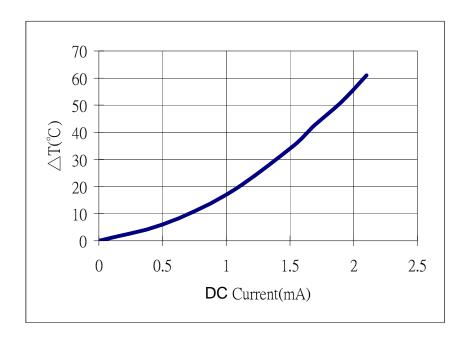




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18 Curve:

IDC(A)	$\triangle T(^{\circ}C)$	surface temp($^{\circ}$ C)	time(minute)
0	0	25	30
0.5	6	31	30
1.0	17	42	30
1.5	34	59	30
1.7	43	68	30
1.9	51	76	30
2.1	61	86	30



Temperature test conditions:

- 1. Start as the atmosphere temp. @25 $^{\circ}$ C.
- 2. Take the reading once it becomes stable.
- 3. Need to wait 90Sec at least, then change to the next applied current value.